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(54) DIODE ARRAY SPECTROPHOTOMETER

(57)Abstract:

PROBLEM TO BE SOLVED: To secure a diffraction grating thermally and mechanically to an inlet slit and a diode array by providing an inlet slit unit, a diffraction grating, a diode array, a casing for determining the relative position of inlet slit and diode array, etc.

SOLUTION: The diode array spectrophotometer comprises an inlet slit unit, a diffraction grating 4, a diode array, a casing 1 for determining the relative position of inlet slit and diode array having a truncated conical opening 7, and at least three filling elements arranged between the outer faces of a rotary grating holder 2 having tubular sleeve outer face. This structure can secure a diffraction grating thermally and mechanically.

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